

## **OptiMOS™3** Power-Transistor

#### **Features**

- N-channel, normal level
- Excellent gate charge x R DS(on) product (FOM)
- Very low on-resistance R DS(on)
- 150 °C operating temperature
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target application
- Ideal for high-frequency switching and synchronous rectification
- Halogen-free according to IEC61249-2-21

Туре	BSC190N15NS3 G
	1 0 8 7 6 5 1 2 3 4 4 5 1 5 1 5 1 5 1 5 1 5 1 5 1 5 1 5 1
Package	PG-TDSON-8
Marking	190N15NS

## **Product Summary**

V <sub>DS</sub>	150	٧
R <sub>DS(on),max</sub>	19	mΩ
ID	50	Α







# **Maximum ratings,** at $T_j$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C	50	А
		T <sub>C</sub> =100 °C	33	1
Pulsed drain current <sup>2)</sup>	/ <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	200	1
Avalanche energy, single pulse	E <sub>AS</sub>	$I_{\rm D}$ =50 A, $R_{\rm GS}$ =25 Ω	170	mJ
Gate source voltage <sup>3)</sup>	V <sub>GS</sub>		±20	V
Power dissipation	$P_{\text{tot}}$	T <sub>C</sub> =25 °C	125	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 150	°C
IEC climatic category; DIN IEC 68-1			55/175/56	



Parameter	Symbol	bol Conditions Values		Unit		
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R <sub>thJC</sub>		-	-	1	K/W
Thermal resistance, junction - ambient	$R_{\mathrm{thJA}}$	6 cm2 cooling area <sup>3)</sup>	_	-	50	

# **Electrical characteristics,** at $T_j$ =25 °C, unless otherwise specified

#### Static characteristics

Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	150	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=90~\mu{\rm A}$	2	3	4	
Zero gate voltage drain current $I_{DSS}$ $V_{DS}=120 \text{ V}, V_{GS}=0 \text{ V}$ $T_j=25 \text{ °C}$		$V_{\rm DS}$ =120 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	1	0.1	1	μA
		V <sub>DS</sub> =120 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	1	10	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	1	1	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10 V, I <sub>D</sub> =50 A	ı	16	19	mΩ
		V <sub>GS</sub> =8 V, I <sub>D</sub> =25 A	1	16	20	
Gate resistance	R <sub>G</sub>		ı	2.4	-	Ω
Transconductance	$g_{ ext{fs}}$	V <sub>DS</sub>  >2 I <sub>D</sub>  R <sub>DS(on)max</sub> , I <sub>D</sub> =50 A	29	57	-	s

<sup>1)</sup>J-STD20 and JESD22

<sup>&</sup>lt;sup>2)</sup> See figure 3

 $<sup>^{3)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^2$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss		-	1820	2420	pF
Output capacitance	C <sub>oss</sub>	V <sub>GS</sub> =0 V, V <sub>DS</sub> =75 V, f=1 MHz	_	214	285	1
Reverse transfer capacitance	C <sub>rss</sub>		-	5	-	
Turn-on delay time	t <sub>d(on)</sub>		_	15	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =75 V, V <sub>GS</sub> =10 V,	-	53	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =50 A, $R_{\rm G}$ =1.6 Ω	-	25	-	
Fall time	t <sub>f</sub>		-	6	-	1
Gate Charge Characteristics <sup>5)</sup>		<del>,</del>				
Gate to source charge	Q <sub>gs</sub>		-	10	-	nC
Gate to drain charge	$Q_{gd}$	., -5., , 50.	-	4	-	
Switching charge	$Q_{sw}$	V <sub>DD</sub> =75 V, / <sub>D</sub> =50 A, V <sub>GS</sub> =0 to 10 V	-	9	-	
Gate charge total	$Q_g$		-	23	31	
Gate plateau voltage	V <sub>plateau</sub>		ı	5.7	1	٧
Output charge	Q oss	V <sub>DD</sub> =75 V, V <sub>GS</sub> =0 V	1	60	79	nC
Reverse Diode						
Diode continous forward current	Is	T -25 °C	-	-	50	Α
Diode pulse current	/ <sub>S,pulse</sub>	T <sub>C</sub> =25 °C	-	-	200	
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =50 A, T <sub>j</sub> =25 °C	-	1	1.2	V
Reverse recovery time	t rr	V <sub>R</sub> =75 V, I <sub>F</sub> =I <sub>S</sub> ,	-	130	-	ns
Reverse recovery charge	Q <sub>rr</sub>	d <i>i</i> <sub>F</sub> /d <i>t</i> =100 A/μs	-	385	-	nC

 $<sup>^{5)}</sup>$  See figure 16 for gate charge parameter definition

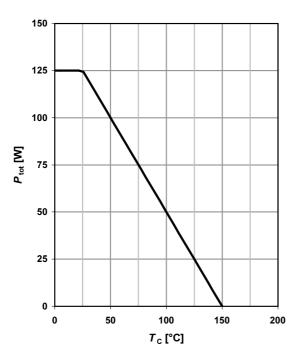


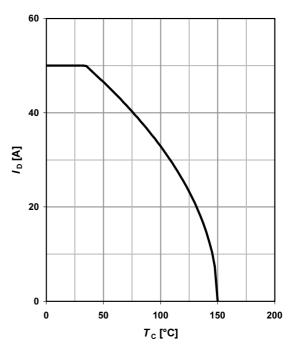
## 1 Power dissipation

# $P_{\text{tot}}$ =f( $T_{\text{C}}$ )

## 2 Drain current

$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$

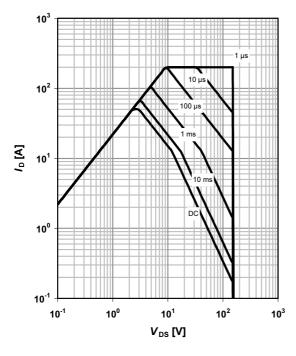




## 3 Safe operating area

$$I_D$$
=f( $V_{DS}$ );  $T_C$ =25 °C;  $D$ =0

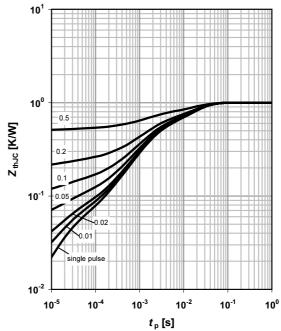
parameter:  $t_p$ 



## 4 Max. transient thermal impedance

$$Z_{thJC}$$
=f( $t_p$ )

parameter:  $D = t_p/T$ 

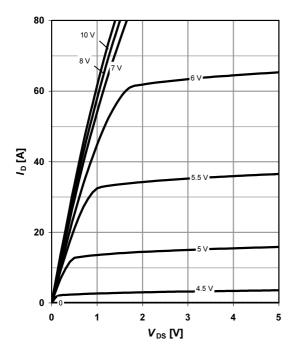




## 5 Typ. output characteristics

 $I_D$ =f( $V_{DS}$ );  $T_j$ =25 °C

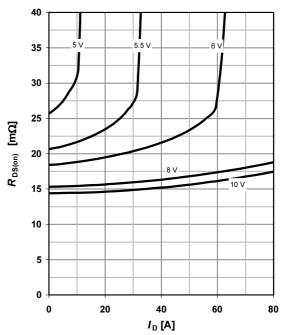
parameter: V<sub>GS</sub>



## 6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f( $I_D$ );  $T_j$ =25 °C

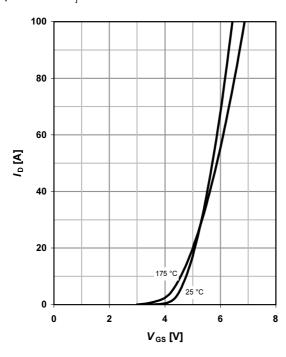
parameter: V<sub>GS</sub>



## 7 Typ. transfer characteristics

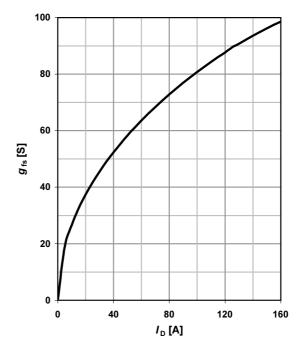
 $I_D = f(V_{GS}); |V_{DS}| > 2|I_D|R_{DS(on)max}$ 

parameter:  $T_j$ 



## 8 Typ. forward transconductance

 $g_{fs}$ =f( $I_D$ );  $T_j$ =25 °C





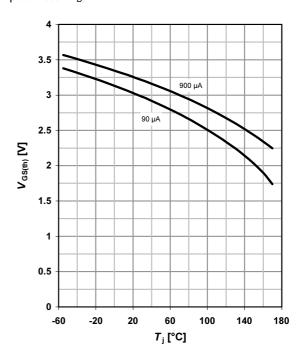
#### 9 Drain-source on-state resistance

 $R_{DS(on)}$ =f( $T_j$ );  $I_D$ =50 A;  $V_{GS}$ =10 V

## 60 55 50 45 40 35 30 25 20 15 10 5 0 -60 -20 20 60 140 180 $T_j$ [°C]

## 10 Typ. gate threshold voltage

 $V_{\rm GS(th)}$ =f( $T_{\rm j}$ );  $V_{\rm GS}$ = $V_{\rm DS}$ parameter:  $I_{\rm D}$ 

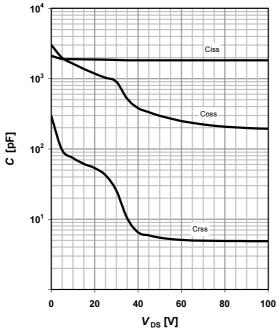


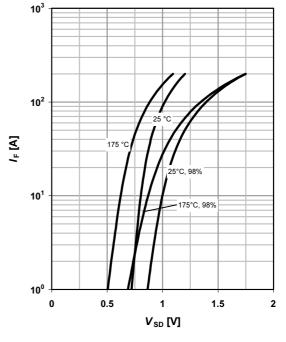
## 11 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$ 

# $I_{\rm F}$ =f( $V_{\rm SD}$ ) parameter: $T_{\rm j}$

12 Forward characteristics of reverse diode



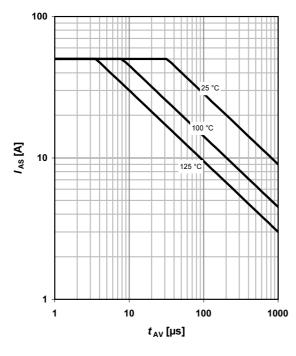




#### 13 Avalanche characteristics

 $I_{\mathsf{AS}}$ =f( $t_{\mathsf{AV}}$ );  $R_{\mathsf{GS}}$ =25  $\Omega$ 

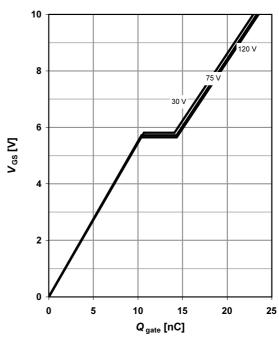
parameter:  $T_{j(start)}$ 



# 14 Typ. gate charge

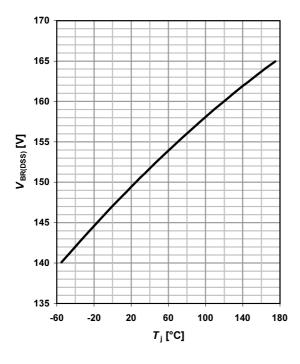
 $V_{\rm GS}$ =f(Q  $_{\rm gate}$ );  $I_{\rm D}$ =50A pulsed

parameter:  $V_{\rm DD}$ 

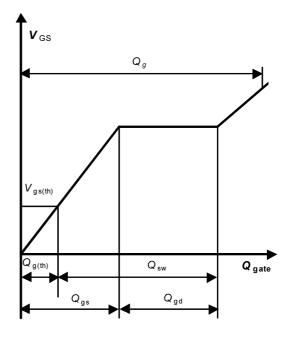


## 15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f( $T_j$ );  $I_D$ =1 mA

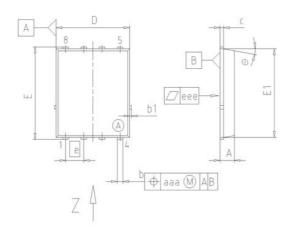


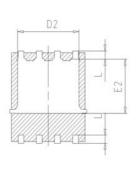
## 16 Gate charge waveforms

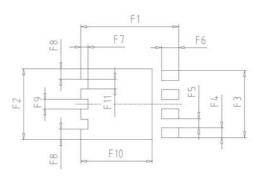


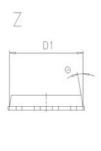


## **PG-TDSON-8 Outline**

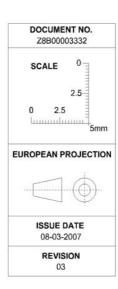








DIM	MILLIM	IETERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	0.90	1.10	0.035	0.043	
b	0.34	0.54	0.013	0.021	
b1	0.02	0.22	0.001	0.008	
С	0.15	0.35	0.006	0.014	
D=D1	4.95	5.35	0.195	0.211	
D2	4.20	4.40	0.165	0.173	
E	5.95	6.35	0.234	0.250	
E1	5.70	6.10	0.224	0.240	
E2	3.40	3.80	0.134	0.150	
e	1.27		0.0	50	
N	8			8	
L	0.45	0.65	0.018	0.026	
0	8.5°	11.5°	8.5°	11.5	
aaa	0.25		0.0	10	
eee	0.0	)5	0.002		
F1	6.75	6.95	0.266	0.274	
F2	4.60	4.80	0.181	0.189	
F3	4.36	4.56	0.172	0.180	
F4	0.55	0.75	0.022	0.030	
F5	0.52	0.72	0.020	0.028	
F6	1.10	1.30	0.043	0.051	
F7	0.40	0.60	0.016	0.024	
F8	0.60	0.80	0.024	0.031	
F9	0.53	0.73	0.021	0.029	
F10	4.90	5.10	0.193	0.201	
F11	0.53	0.73	0.021	0.029	





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